Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/690,463	CHENG, JYH-NAN		
Examiner	Art Unit		
TAN N. TRAN	2826		

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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